## nexperia

## **Quarterly Reliability Monitoring Results**

Quarters: Q1/2021 to Q4/2021

Based on structural	similarity
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Supplier		User Part Number					
Nexperia B.V.		PMEG3020EPA					
Name of Laboratory		Part Description					
		Nexperia DHAM	Schottky				
Assembly reliability labs Based on AEC-Q101 Test		MCD package					
		Test Conditions	Duration	# Lots	# Quantity	# Rejects	
	TEST Pre- and Post-Stress						
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below	
# A1	<b>PC</b> Preconditioning	JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering	24 hours 168 hours 3 cycles	113	9040	0	
# B1	<b>HTRB</b> High Temperature Reverse Bias	$ \begin{array}{l} \text{MIL-STD-750-1} \\ \text{M1038 Method A} \\ \text{Tj} = \text{Tjmax},  \text{Vr} = 100\% \text{ of max. datasheet} \\ \text{reverse voltage}^{[1]} \end{array} $	1000 hours	116	9280	0	
# A4	<b>TC</b> Temperature Cycling	JESD22-A104 -65 °C to Tjmax, not to exceed 150°C	1000 cycles	28	2240	0	
# A3 alt	<b>AC</b> Autoclave	JESD22-A102 Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)	96 hours	28	2240	0	
# A2 alt	<b>H3TRB</b> High Humidity High Temperature Reverse Bias	JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of rated reverse voltage <sup>[1], [2]</sup>	1000 hours	28	2240	0	
# A5	<b>IOL</b> Intermittent Operating Life	MIL-STD-750 Method 1037 ton = toff, devices powered to insure $\Delta Tj$ =	1000 hours	29	2320	0	
# C8	<b>RSH</b> Resistance to Solder Heat	JESD22-A111 260 °C ± 5 °C	10 s	n.a.	n.a.	n.a.	
# C10	<b>SD</b> Solderability	J-STD-002		63	630	0	

[1] The physical limitations of Schottky diodes have to be considered (thermal runaway).

[2] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Nexperia	F (hrs)
DHAM Schottky 9280 0 0.46 2.19	E+09

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